

SLOVENSKI STANDARD oSIST prEN IEC 61987-100:2024

01-september-2024

Merjenje in nadzor industrijskega procesa - Strukture podatkov in elementov

Industrial-process measurement and control - Data structures and elements

Mesure et commande des processus industriels - Structures et éléments de données

Ta slovenski standard je istoveten z: prEN IEC 61987-100:2024

Acument Proview

ICS:

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https://st 25.040.40 ai/ca Merjenje in krmiljenje) 128-e43 Industrial process 160 fdb/osist-pren-iec-61987-100-2024 industrijskih postopkov measurement and control 35.240.50 Uporabniške rešitve IT v IT applications in industry industriji

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65E/1089/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

	PROJECT NUMBER:					
	DATE OF CIRCULATION:	CLOSING DATE FOR VOTING:				
	2024-08-02	2024-10-25				
SUPERSEDES DOCUMENTS:						
	65E/1074/CD, 65E/1085/CC					

IEC SC 65E : DEVICES AND INTEGRATION IN ENTERPRISE SYSTEMS				
SECRETARIAT: SECRETARY:				
United States of America Mr David Richmond	Mr David Richmond			
OF INTEREST TO THE FOLLOWING COMMITTEES: PROPOSED HORIZONTAL STANDARD:	PROPOSED HORIZONTAL STANDARD:			
SC 3D,TC 65,SC 65A,SC 65B,SC 65C				
Other TC/SCs are requested to indicate their intrany, in this CDV to the secretary.	erest, if			
FUNCTIONS CONCERNED:				
EMC Environment Quality assurance Safety				
Submitted for CENELEC parallel voting	NG			
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Attention IEC-CENELEC parallel voting				
The attention of IEC National Committees, members of CENELEC, is drawn to the fact that this Committee Draft				
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TITLE:

Industrial-process measurement and control - Data structures and elements

PROPOSED STABILITY DATE: 2026

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20 21 22	INDUSTRIAL-PROCESS MEASUREMENT AND CONTROL - DATA STRUCTURES AND ELEMENTS							
23 24			FORE\	WORD				
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58	58 The text of this International Standard is based on the following documents:							
			Draft	Report on voting				
			65E/937/NP	65E/992/RVN				

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Full information on the voting for its approval can be found in the report on voting indicated in

61 the above table.

The language used for the development of this International Standard is English.

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